

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	Docket Number (Optional) TW1-8520	Application Number NEW 10/717,316
	Applicant(s) Allan Rosencwaig et al.	
	Filing Date HEREWITH	Group Art Unit Unknown 2877

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<i>[Signature]</i>	*AA	3,887,392	06/03/1975	Tang	134	1	11/23/1973
<i>[Signature]</i>	*AB	5,261,965	11/16/1993	Moslehi	134	1	08/28/1992
<i>[Signature]</i>	*AC	5,306,671	04/26/1994	Ogawa et al.	437	225	06/21/1991
<i>[Signature]</i>	*AD	5,316,970	05/31/1994	Batchelder et al.	250	423P	06/05/1992
<i>[Signature]</i>	*AE	5,439,596	08/08/1995	Ohmi et al.	210	748	07/02/1992
<i>[Signature]</i>	*AF	5,449,411	09/12/1995	Fukuda et al.	118	723 MP	10/19/1993
<i>[Signature]</i>	*AG	5,798,837	08/25/1998	Aspnes et al.	356	369	07/11/1997
<i>[Signature]</i>	*AH	6,325,078	12/04/2001	Kamieniecki	134	1.3	01/07/1998

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
<i>[Signature]</i>	*AI	WO 95/04681	01/05/1995	PCT	C23G	1/00		
<i>[Signature]</i>	*AJ	1043700	11/06/1996	Japan	B08B	3/12		
<i>[Signature]</i>	*AK	WO 98/05066	02/05/1998	PCT	H01L	21/66		
<i>[Signature]</i>	*AL	WO 99/35677	07/15/1999	PCT	H01L	21/306		
<i>[Signature]</i>	*AM	4-357836	12/10/1999	Japan	H01L	21/304		

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

<i>[Signature]</i>	*AN	K. Imen et al., "Laser-assisted micron scale particle removal," <i>App. Phys. Lett.</i> , Vol. 58, No. 2, 14 January 1991, pp. 203-205.
<i>[Signature]</i>		
<i>[Signature]</i>		

Examiner <i>[Signature]</i>	Date Considered 23 July 2004
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	